

WAFER-LEVEL TEST STRUCTURE FOR EDGE-EMITTING  
SEMICONDUCTOR LASERS

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ABSTRACT OF THE DISCLOSURE

10           Wafer-level stage testing of semiconductor lasers can be facilitated by  
directing a light beam emitted from the semiconductor laser toward a direction different  
from a path of the light beam as originally emitted from the laser. A test structure can  
be coupled to a back facet of the laser and can include a first region separated from a  
second region by an inclined interface. When a light beam is emitted from the laser, the  
15          light beam can be received on the inclined interface and then directed toward a light  
detector for detection and evaluation.